Metrology and Instrumentation Development (MID)

MID at NSLS-II
- This flexible beamline will enable development of novel x-ray instrumentation and methods for NSLS-II beamlines to provide cutting edge synchrotron science for years to come.
- MID can also support additional tests as needed for users from compatible fields (materials science, astronomy, etc.).

Examples of Science Areas & Impact
- X-RAY OPTICS: Optimal performance of mirrors, crystals, gratings and refractive optics for use in imaging and spectroscopy will be proven “at-wavelength” using reflectometry, topography and interferometric methods
- DETECTORS: High efficiency, bandwidth and resolution can be reached with feedback from beamline test, ultimately delivering arrayed spectroscopic detectors and diagnostics for high-throughput diffraction, spectroscopy and imaging
- ENVIRONMENTS, POSITIONING AND COMPOUND SYSTEMS: Flexible configuration enables collaborative development of x-ray end stations for a wide variety of techniques
- POLARIMETRY AND TIMING: New techniques and devices enable advances in materials science

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